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- Members of the Texas Instruments
 Widebus™ Family
- Inputs Are TTL-Voltage Compatible
- 3-State Outputs Drive Bus Lines Directly
- Provide Extra Bus Driving/Latches Necessary for Wider Address/Data Paths or Buses With Parity
- Flow-Through Architecture Optimizes PCB Layout
- Distributed V_{CC} and GND Pin Configuration Minimizes High-Speed Switching Noise
- EPIC™ (Enhanced-Performance Implanted CMOS) 1-µm Process
- 500-mA Typical Latch-Up Immunity at 125°C
- Package Options Include Plastic Thin Shrink Small-Outline (DGG) Packages, 300-mil Shrink Small-Outline (DL) Packages Using 25-mil Center-to-Center Pin Spacings, and 380-mil Fine-Pitch Ceramic Flat (WD) Packages Using 25-mil Center-to-Center Pin Spacings

description

These 20-bit latches feature 3-state outputs designed specifically for driving highly capacitive or relatively low-impedance loads. They are particularly suitable for implementing buffer registers, I/O ports, bidirectional bus drivers, and working registers.

The 'ACT16841 can be used as two 10-bit latches or one 20-bit latch. The 20 latches are transparent D-type. While the latch-enable (1LE or 2LE) input is high, the Q outputs of the corresponding 10-bit latch follow the data (D) inputs. When LE is taken low, the Q outputs are latched at the levels that were set up at the D inputs.

54ACT16841 . . . WD PACKAGE 74ACT16841 . . . DGG OR DL PACKAGE (TOP VIEW)



A buffered output-enable $(1\overline{OE} \text{ or } 2\overline{OE})$ input can be used to place the outputs of the corresponding 10-bit latch in either a normal logic state (high or low logic levels) or a high-impedance state. In the high-impedance state, the outputs neither load nor drive the bus lines significantly.

OE does not affect the internal operation of the latches. Old data can be retained or new data can be entered while the outputs are in the high-impedance state.



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description (continued)

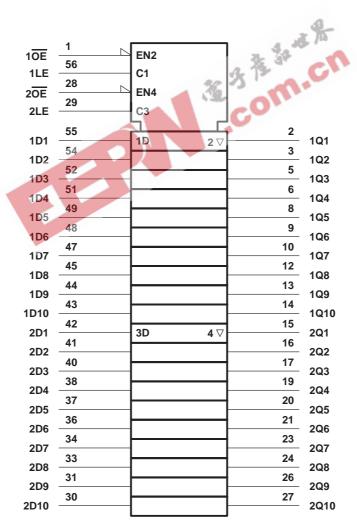
The 74ACT16841 is packaged in TI's shrink small-outline package (DL), which provides twice the I/O pin count and functionality of standard small-outline packages in the same printed-circuit-board area.

The 54ACT16841 is characterized for operation over the full military temperature range of -55°C to 125°C. The 74ACT16841 is characterized for operation from -40°C to 85°C.

FUNCTION TABLE (each 10-bit latch)

	INPUTS	OUTPUT	
OE	LE	D	Q
L	Н	Н	Н
L	Н	L	L
L	L	Χ	Q ₀
Н	X	Χ	Z

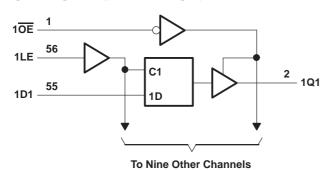
logic symbol†

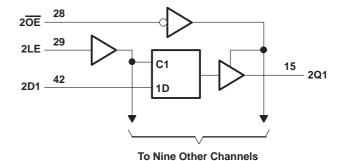


[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.



logic diagram (positive logic)





absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V _{CC}	0.5 V to 7 V
Input voltage range, V _I (see Note 1)	\dots -0.5 V to V _{CC} + 0.5 V
Output voltage range, V _O (see Note 1)	$-0.5 \text{ V to V}_{CC} + 0.5 \text{ V}$
Input clamp current, I_{IK} ($V_I < 0$ or $V_I > V_{CC}$)	±20 mA
Output clamp current, I _{OK} (V _O < 0 or V _O > V _{CC})	±50 mA
Continuous output current, I_O ($V_O = 0$ to V_{CC})	±50 mA
Continuous current through V _{CC} or GND	±500 mA
Maximum package power dissipation at T _A = 55°C (in still air) (see Note 2): DGG	package 1 W
DL pa	ackage1.4 W
Storage temperature range, T _{stq}	–65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.
 - 2. The maximum package power dissipation is calculated using a junction temperature of 150°C and a board trace length of 750 mils.

recommended operating conditions (see Note 3)

			ACT1684	41	74ACT16841			UNIT
		MIN	NOM	MAX	MIN	NOM	MAX	ONIT
VCC	Supply voltage	4.5	5	5.5	4.5	5	5.5	V
VIH	High-level input voltage	2		7	2			V
VIL	Low-level input voltage		Š	0.8			0.8	V
VI	Input voltage	0	PA	VCC	0		VCC	V
Vo	Output voltage	0	1/2	VCC	0		VCC	V
ІОН	High-level output current		3	-24			-24	mA
loL	Low-level output current	,0,	5	24			24	mA
Δt/Δν	Input transition rise or fall rate	0		10	0		10	ns/V
TA	Operating free-air temperature	-55		125	-40		85	°C

NOTE 3: Unused inputs must be held high or low to prevent them from floating.

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

DADAMETED	TEST CONDITIONS	V	T,	λ = 25°C	54AC	54ACT16841		74ACT16841	
PARAMETER	TEST CONDITIONS	vcc -	MIN	TYP MA	(MIN	MAX	MIN	MAX	UNIT
	Jour - 50 uA	4.5 V	4.4		4.4		4.4		
	I _{OH} =-50 μA	5.5 V	5.4		5.4		5.4		
Voн	I _{OH} = -24 mA	4.5 V	3.94		3.8		3.8		V
	IOH = -24 IIIA	5.5 V	4.94		4.8		4.8		
	$I_{OH} = -75 \text{ mA}^{\dagger}$	5.5 V			3.85	JAJ.	3.85		
	lo 50 uA	4.5 V		0.	1	0.1		0.1	V
	I _{OL} = 50 μA	5.5 V		0.	1	0.1		0.1	
VoL	Jan. 24 mA	4.5 V		0.3	5 5	0.44		0.44	
	I _{OL} = 24 mA	5.5 V		0.3	3 8	0.44		0.44	
	$I_{OL} = 75 \text{ mA}^{\dagger}$	5.5 V			Q'Q	1.65		1.65	
lį	V _I = V _{CC} or GND	5.5 V		±0.	1	±1		±1	μΑ
loz	$V_O = V_{CC}$ or GND	5.5 V		±0.	5	±5		±5	μΑ
lcc	$V_I = V_{CC}$ or GND, $I_O = 0$	5.5 V			3	80		80	μΑ
∆I _{CC} ‡	One input at 3.4 V, Other inputs at V _{CC} or GND	5.5 V		0.		1		1	mA
Ci	V _I = V _{CC} or GND	5 V	36	3	1				pF
Co	V _O = V _{CC} or GND	5 V	137	11					pF

[†] Not more than one output should be tested at a time, and the duration of the test should not exceed 10 ms.

timing requirements over recommended operating free-air temperature range, V_{CC} = 5 V \pm 0.5 V (unless otherwise noted) (see Figure 1)

		T _A = 25°C	54ACT16841	74ACT16841	UNIT	
			MIN MAX	MIN MAX	MIN MAX	UNIT
t _W	Pulse duration, LE high	e duration, LE high		4	4	ns
t _{Su} Setup time, data before LE↓			1.5	1.5	1.5	ns
t _h Hold time, data after LE↓		High	3	P-3()	3	no
		Low	4.5	4.5	4.5	ns

switching characteristics over recommended operating free-air temperature range, V_{CC} = 5 V \pm 0.5 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то	TO T _A = 25°C			54ACT16841		74ACT16841		UNIT
PARAMETER	(INPUT)	(OUTPUT)	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
^t PLH	D	Q	4	7.1	10.3	4	11.8	4	11.8	no
^t PHL	D		3.2	6.9	11	3.2	12.2	3.2	12.2	ns
t _{PLH}	LE	Q	4.5	7.7	11.3	4.5	12.7	4.5	12.7	ns I
^t PHL			4.3	7.8	11.4	4.3	12.7	4.3	12.7	
^t PZH		_	3.1	6.4	10.1	3.1	11.3	3.1	11.3	no
t _{PZL}	ŌĒ	Q	3.8	7.6	12.1	3.8	13.7	3.8	13.7	ns
^t PHZ	ŌĒ	== 0	4	7.3	9.5	4	10.2	4	10.2	ne
t _{PLZ}		Q	4	6.8	8.9	4	9.6	4	9.6	ns

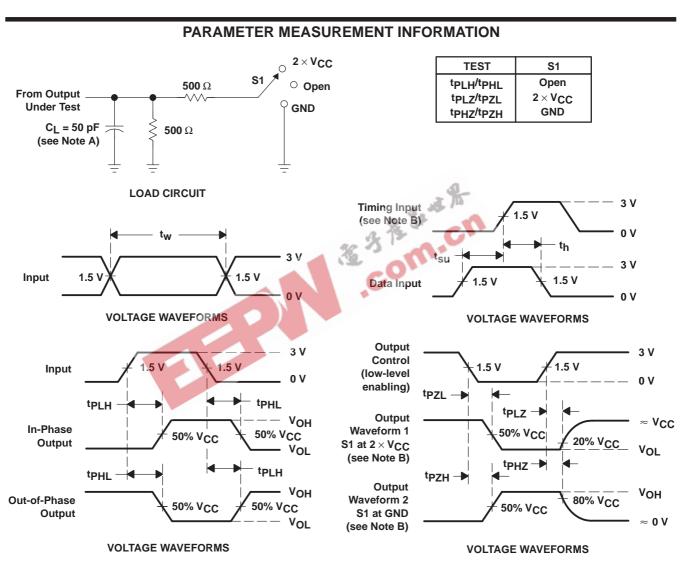


[‡]This is the increase in supply current for each input that is at one of the specified TTL voltage levels rather than 0 V or VCC.

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operating characteristics, $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$

PARAMETER				TEST CONDITIONS		
C _{pd}	Power dissipation capacitance	Outputs enabled	C 50 pE	f = 1 MHz	41	,,,
		Outputs disabled	$C_L = 50 \text{ pF},$	I = I IVIDZ	10	p⊦



NOTES: A. C_L includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, Z_O = 50 Ω , t_f = 3 ns, t_f = 3 ns.
- D. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms



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